

Application/Control No	٥.
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10/717,562 Examiner

Joseph Nguyen

Applicant(s)/Patent under Reexamination

ISHIKAWA ET AL.

Art Unit

2815

	SEVD	CHED	
	SEAR	CHED	
Class	Subclass	Date	Examiner
257	59,20	1/16/2005	JN
257	258	1/16/2005	JN
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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(INCLUDING	RCH NOT SEARCH	STRATEGY)
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EAST		1/16/2005	JN